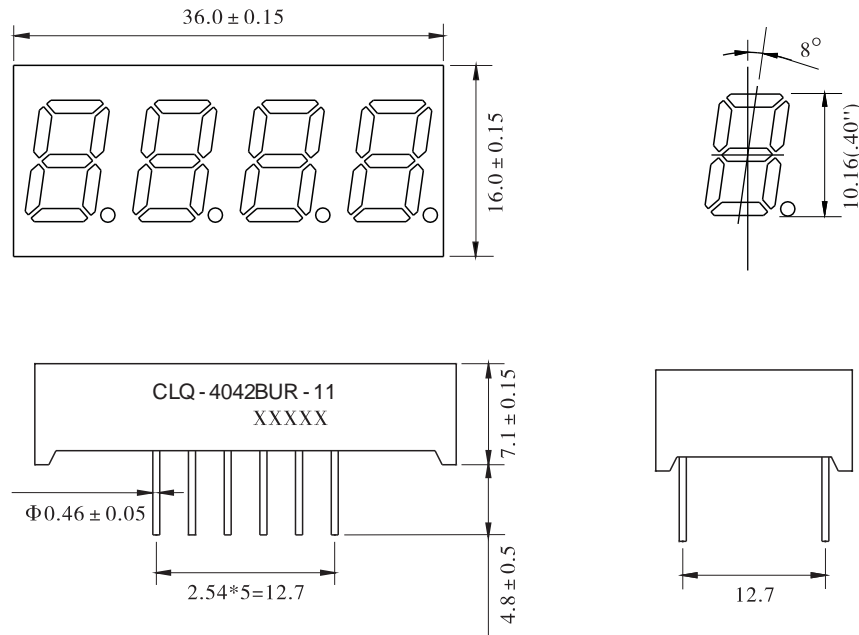
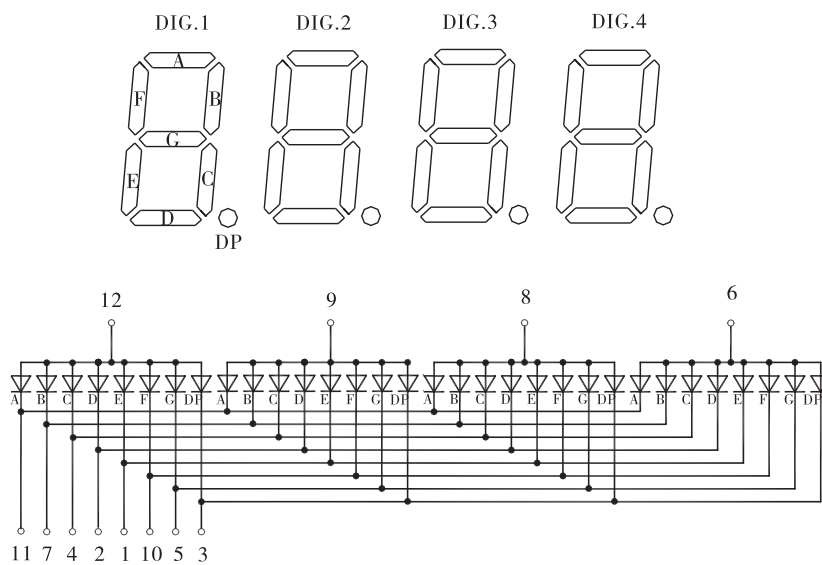


Descriptions

1. Emitting color :Red
2. Lens color:White Diffuseb
3. Dice material:AlGaInP/GaAs

Outline drawing

 Tolerance is $\pm 0.25\text{mm}$ unless otherwise noted

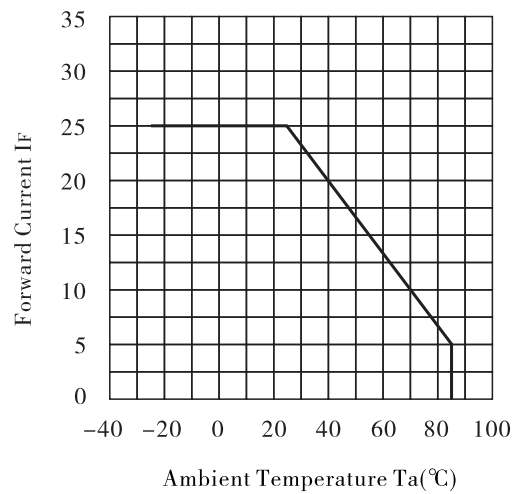
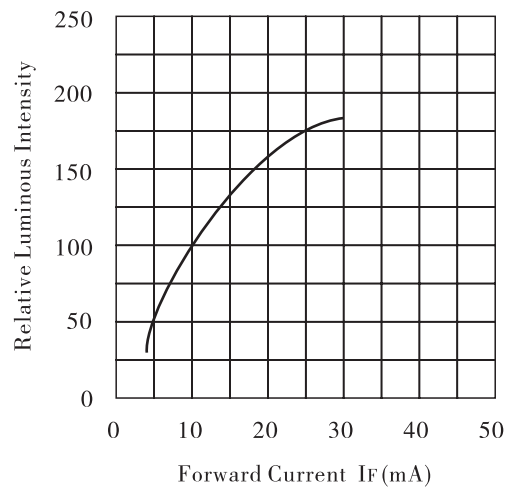
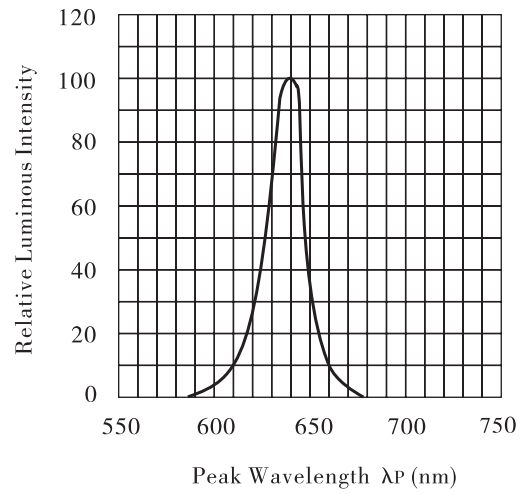
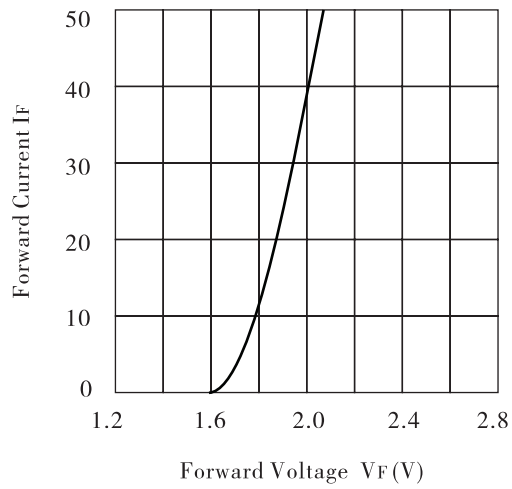
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Electrical optical characteristics (Ta=25°C)

Parameter	Symbol	Red			Unit	Test Condition
		Min	Typ	Max		
Forward Voltage	V _F		2.0	2.3	V	IF=20mA
Luminous Intensity	I _V	4			med	IF=10mA
Peak Wavelength	λ _P		640		nm	IF=20mA
Spectral Line half-width	Δλ		20		nm	IF=20mA
Reverse Leakage Current	I _R			30	μA	V _R =5V

Absolute maximum parameters (Ta=25°C)

Parameter	Symbol	Condition	Rating	Unit
Power Dissipation	PD	---	60	mW
Reverse Voltage	VR	I _R =50 μ A	5	V
Forward Average Current	IF	---	25	mA
Temperature coefficient	I/C	---	0.4	mA/°C
Pulse Current	IFP	Duty=1/10,1kHz	100	mA
Operating Temperature Range	T _{opr}	---	-25 ~ +85	°C
Storage Temperature Range	T _{stg}	---	-30 ~ +100	°C
Soldering Condition	T _{sd}	---	265°C/5sec	°C

Typical Electro-Optical characteristic curves (Ta=25°C)


Reliability test conditions

Test Item	Test Condition	Result	Judgment criteria
Consecutive operating life test	IF=20mA, T=25°C, t=168h	0/12	Forward Voltage $V_F(V) = \text{Upper Limit} \times 1.2$ Reverse Leakage Current $I_R(\mu A) = \text{Upper Limit} \times 2.0$ Luminous Intensity Iv (mcd) = Lower Limit $\times 0.7$
High temperature storage life test	T=100°C, t=168h	0/12	
Low temperature storage life test	T=-25°C, t=168h	0/12	
high Temperature humidity storage life test	T=85 ± 2°C, RH=85% ± 3, t=168h	0/12	
Temperature cycle test	-25°C~25°C~100°C, 30min 5min 30min 10cycles	0/12	
Thermal shock test	100°C 0°C 5min 5min 20 cycles	0/12	
Soldering heat test	T=260 ± 5°C, t=10s ± 1s	0/12	
Solderability test	T=230 ± 5°C, t=5s ± 0.5s	0/12	Steeped Part ≥ 95%
Fall test	h=100cm, Free fall, 3times	0/12	Intact
Terminal strength test	W=9.8N, t=30 ± 5s	0/12	
Lead Bending test	W=4.9N, 2times	0/12	